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TABLE OF CONTENTS

ARMOR: Architectural Reliability via Multi-Objective Optimization for Early-Exit Neural Networks 1
Michalis Kontos, Georgios Konstantinidis, Theocharis Theocharides, Maria K. Michael

Radiation Hardened and Self-Recoverable Latch Design for Quad-Node Upset Mitigation 5
Evangelos Paparsenos, Yiorgos Tsiatouhas

STA-Based Single Event Transient Propagation in Advanced Technology Nodes 9
Nikolaos Chatzivangelis, Marios Karagiannis, Christos Georgakidis, Nikolaos Sketopoulos
Marko Andjelkovic, Luigi Dilillo, Christos Sotiriou

Impact and Characterization of Single Event Failures in Hyperdimensional Computing Hardware Accelerator 13
Marcello Barbirotta, Marco Angioli, Rocco Martino, Federico Frontera, Antonio Mastrandrea
Mauro Olivieri

Actuarial Voltage Scaling (AVS+): A Statistical Reliability Framework for Reducing Guardbands in Systolic Arrays 17
Larisa Goffman-Vinopal

Soft-Error Sensitivity Analysis of Adder Tree architectures for Compute-In-Memory Accelerators 21
Panagiotis Chaidos, Alexis Maras, Georgios Alexandris, Dimitrios Soudris, Sotirios Xydis

Shooting Neutrons at Neurons: Radiation Testing of a Spiking Neural Network on Flash-Based FPGAs 25
Wim Nijsink, Bruno Endres Forlin, Amirreza Yousefzadeh, Marco Ottavi

Machine Learning Approach for Cross-Technology Prediction of the Generated Single Event Transient 29
Konstantinos Varakliotis, Nikolaos Zazatis, Marko Andjelkovic, Nikolaos Chatzivangelis, Fabian Vargas
Milos Krstic, Christos Sotiriou

Towards Resilient Transformer-Encoders: Fault Injection and Hardware Agnostic Error Mitigation 33
Vishal Thomas, Ussama Zahid, Giulio Gambardella, Sumeet Sapkal, Haralampos-G. Stratigopoulos
Brian Clerkin

Auto-Generating Ageing Self-Tests with Hardware in the Loop for Commercial Microcontrollers 37
Leandro Lanzieri, Goerschwin Fey, Holger Schlarb, Thomas C. Schmidt

NURSE: A Distributed Architecture for Runtime Fault Management in Processor Designs 41
Ashwin Santhosh, Artur Jutman, Endri Kaja, Wolfgang Ecker, Maksim Jenihhin

Re-sequencing ECC and Built-In Self-Repair with In-Page Fault Scrambling for Enhancing Yield and Reliability of Flash Memory 45
Shyue-Kung Lu, Qian-Rui Dong

An interpretable data-driven framework for variable group selection in high-dimensional manufacturing test data 49
Yang Yang, Bin Yang, Yiwen Liao Data

Exploration of Machine Learning-Based Test Methodologies in High-Volume Manufacturing RF Testing 55
Hakan Cetin, Alexandre Leon, Manuel J. Barragan, Philippe Ferrari

Test Sample Ranking for Fault Detection in Decision Tree-based Inference Model 61
Antonio Emmanuele, Mario Barbareschi, Alberto Bosio

Advances in Testing and Reliability Benchmarks 67
Francesco Angione, Paolo Bernardi, Nicola Di Gruttola Giardino, Gabriele Filipponi, Giusy Iaria Giacomo Perlo, Irith Pomeranz, Antonio Porsia, Annachiara Ruospo, Ernesto Sanchez, Vittorio Turco

A real opportunity or still a promise? The current status of the RISC-V ecosystem 77
Elia Lazzeri, Gianluca Furano, Luca Cassano

Sample-efficient Performance Tuning of mixed-signal ASICs via Probabilistic Surrogates 86
Tim Strobel, Nima Shahpari, Sarah Rottacker, Roland Rösslhuber, Jens Anders

A Single-Cycle, Area-Efficient Calibration Method for TDC-based Timing Monitors 92
Madiha A. Sheikh, Marco Ottavi

Scalable Design-for-Calibration of Programmable Silicon Photonics 98
Lawrence Schlitt, Priyank Kalla, Steve Blair

EXACT: Edge-eXplainable Autonomous Causal Telemetry for Silicon Lifecycle Management 104
Hsiao-Ping Ni, Eduardo Ortega, Krishnendu Chakrabarty

Robustness Assessment of Edge AI-Based Li-Ion Battery State-Of-Health Prediction 110
Alexandru Ciobotaru, Cosmina Corches, Dan Gota, Szilárd Enyedi, Ovidiu Stan, Liviu Miclea

Off-Chip Super-Resolution AI Model to Support Embedded Memory Diagnosis 116
Simone Anedda, Paolo Bernardi, Matteo Coppetta, Giorgio Insinga, Tommaso Montedoro Annachiara Ruospo, Rudolf Ullmann, Felix Tengler

Testing of a 12 bit SARA And Cand Analog Scan 122
Anthony Coyette, Wim Dobbelaere, Doina Dima, Arlind Billa, Krzysztof Jurga, Vladimir Zivkovic Stephen Sunter

Use of GitHub Copilot Agent Mode for Automated Development in R&D Data Engineering 128
Marco D'Acunzo, Daniele Rossi, Jamal Mohamad Maamoun, Giorgia Cassetta

Gremlins in the Silicon: Why Faulty Chips are Escaping the Fab and Crashing in the Field 132
Mottaqiallah Taouil, Shawn Blanton, Phil Nigh, Adit D. Singh, Said Hamdioui

Exploring Hybrid Brain-Inspired Architectures and Technology Heterogeneity for High Performance AI Applications: Challenges & Solutions 142
Leticia Maria Bolzani Pöhls

TDDB Stress Test Coverage Quantification using Cell-aware Transistor State Stress Model 148
Vladimir A. Zivkovic, Stephan Eggersglüβ, Andreas Glowatz, Daniel Tille

A Holistic Framework to Assess Reliability Issues in Emerging Technologies due to Ageing, Voltage and Temperature Variation 154
Sara Mannaa, Grégory Loubet, Salvatore Pappalardo, Cédric Marchand, Damien Deleruyelle Alberto Bosio, Christoph Lenz, Oskar Baumgartner, Yifan Wang, FranÇois Marc, Chhandak Mukherjee Marina Deng, Cristell Maneux, Ian O'Connord

TDsReCAM: Time-Domain sensing for reliable ReRAM-based Content Addressable Memory 160
Haneen G. Hezayyin, Mahta Mayahinia, Mehdi Tahoori, Sule Ozev

Fault Model-Driven Formal Verification of Cryptographic Hardware Against Fault Attacks 166
Daniel Thirion, George-Cristian Sercaianu, Valentin Egloff, Jean-Marc Daveau, Vincent Beroulle David Hely, Philippe Roche

On Evaluating the Security of TRNG-driven SRAM Scrambling Architecture 172
Manan Kumar Singh, Gaurav Kumar, Kashvi Bansal, Yamuna Prasad, Satyadev Ahlawat

A Chosen-Ciphertext Side-Channel Attack on Protected ML-KEM Using Pairwise Bit-Flipping 178
Ruize Wang, Linus Backlund, Elena Dubrova

FAT-SNN: Fault-Aware Training of Flexible Analog Spiking Neural Networks Using Robust Surrogates 184
Simon Schupp, Tara Gheshlaghi, Priyanjana Pal, Mehdi B. Tahoori

A Ferroelectric nvSRAM PUF with Built-In Grey Bit Masking based on FeCAP–SRAM Interactions 190
Lucas Rhetat, Jean-Philippe Noel, Bastien Giraud, Laurent Grenouillet, Cédric Marchand, Ian O'Connor

SWEET-DREAM: Side-Channel Weakness Evaluation and Enhanced Mitigation for DREAM-CIM 196
Fouwad Jamil Mir, Abdullah Aljuffri, Said Hamdioui, Mottaqiallah Taouil

CODA: Confidence-Driven Adaptive Testing of Analog/Mixed-Signal Circuits Using Gaussian Mixture Models 202
Ankush, Ashiqur Rasul, Anurup Saha, Abhijit Chatterjee

Extending FPGA-based NRZ Test Signals Beyond 100 Gbps 208
David Keezer, Cao Wang, Shengbo Liu, Xiaochun Li, Yindong Xiao

Oscillation-Based Test for mm-Wave Reflection-Type Phase Shifters 214
M. Margalef-Rovira, L. Vincent, E. Pistono, S. Bourdel, M. J. Barragan, P. Ferrari

Hardware Trojans Horses: Two Decades Later, What We Really Know 220
Giorgio Di Natale, Emanuele Valea

A CIM-based Gaussian Random Number Generator for Edge Devices as Security Primitive 230
Fouwad Jamil Mir, Asmae El Arrassi, Said Hamdioui, Mottaqiallah Taouil

Bridging the Speed-Accuracy Gap: Layout-Aware Pre-Silicon Side-Channel Analysis 234
Asmaa Kassimi, Abdullah Aljuffri, Said Hamdioui, Mottaqiallah Taouil

Memory ECC Logic Testing using MBIST 238
Wei Zou, Artur Pogiel, Martin Keim, Albert Au, Jongsin Yun, Luc Romain

Attacks Exploiting On-Chip Instruments and IJTAG Protection 242
Joel Åhlund, Fanny Lundberg, Markus Törmänen, Erik Larsson

Structural Testing Methodology for Deep Neural Networks based on RRAM 246
Emmanouil Anastasios Serlis, Emmanouil Arapidis, Theofilos Spyrou, Anteneh Gebregiorgis Mottaqiallah Taouil, Said Hamdioui, Moritz Fieback

SOLDER: State-Space Oriented Learning with Denoising-Enhanced Representations for PCB Defect Analysis 250
Md Fahim Ul Islam, Krishnendu Chakrabarty

Distributed Delay-Based BIST for Mixed-Signal Circuits in Flexible Electronics 254
Paula Carolina Lozano Duarte, Sule Ozev, Mehdi Tahoori

Exploration of Reference Trimming Schemes for STT-MRAMs 258
Pei-Yun Lin, Jin-Fu Li

Design-for-Testability and Built-In Self-Test Techniques for SRAM-Based Compute-In-Memory Systems 262
Shyue-Kung Lu, Chin-Jung Lee

Path Delay Fault Testable KFDD Circuits with Polynomial Test Pattern Generation 266
Martha Schnieber, Rolf Drechsler

Hierarchical EMFI Analysis on a RISC-V SoC 270
Dillibabu Shanmugam, Zhenyuan Liu, Patrick Schaumont

Encoded Repair Configuration Chains for Die-to-Die Interconnect Test and Repair Language 274
Ashish Reddy Bommana, Anshuman Chandra, Moiz Khan

Beyond Fingerprints: Systematic Design of APUFs for Batch Identification 278
Lina Baolati, Wenjing Rao, Natasha Devroye

Exploiting Near-Memory Computing Resources for Native, Adaptive, and Low-Overhead MBIST 282
S. Ait Belkacem, L. Ammoura, M. Ramirez-Corrales, M.-L. Flottes, P. Girard, J.-P. Noel, A. Virazel

Discovering Unknown Wafermap Patterns Using Cluster-Graph-Based Analytics 286
Qiang Guo, Zixin Shen, Hongliang Lü, Liangliang Yu, Chunlin Ren, Junlin Huang

A Circular Repair Scheme for 3DIC Die-to-Die Interconnects 290
Anshuman Chandra, Moiz Khan, Barbara Działowska, Marta Stępniewska

An Elmore Delay Model Based Test Method for Post-Bond TSVs 296
Zhicheng Shao, Xiaole Cui, Xiaoxin Cui

An Enhanced, Self-Adapting Asynchronous Interface for High-Frequency IJTAG Instruments In Clock Mesh Environments 302
Luc Romain, Katarzyna Wojnowska, Roger Mah, Albert Au, Wei Zou, Martin Keim

Reliability, Test, and Security of Compute-In-Memories 308
Soyed Tuhin Ahmed, Krishnendu Chakrabarty, Jin-Fu Li, Mottaqiallah Taouil, Fouwad Jamil Mir Said Hamdioui, Mehdi Tahoori, Martin Keim, Jongsin Yun

Fast Circuit Analysis via Neighborhood-Guided Maximum Common Subgraph 317
Paolo Bernardi, Lorenzo Cardone, Stefano Quer

Iterative LLM-Based Assertion Generation Using Syntax–Semantic Representations for Functional Coverage–Guided Verification 323
Yonghao Wang, Jiaxin Zhou, Yang Yin, Hongqin Lyu, Zhiteng Chao, Wenchao Ding, Jing Ye Tiancheng Wang, Huawei Li

Efficient Hash-to-Index via Rejection Sampling for Online Fault Detection with Bloom/Cuckoo Filters 329
Elijah Seth Cishugi, Kuan-Hsun Chen, Marco Ottavi

Using Analog IJTAG to Measure ISO 26262 Metrics 335
Bartlomiej Praselski, Stephen Sunter

Special Session: Hardware Security at the Circuit and Layout Levels 341
Sajjad Parvin, Carl Riehm, Nan Du, Ralf Brederlow, Frank Sill Torres, Rolf Drechsler

Introduction to Post Quantum Cryptography for Resource Constrained Systems 349
Leonidas Kosmidis, Sergi Alcaide, Matina Maria Trompouki, Antonio Escobar-Molero, Adam Anglart
Daniel Van Geest, Martin Zuber, Jean-Paul Truong, Andrej Grebenc, Detlef Houdeau